

-30V P-Channel Enhancement Mode MOSFET

Description

The AP20P03DF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

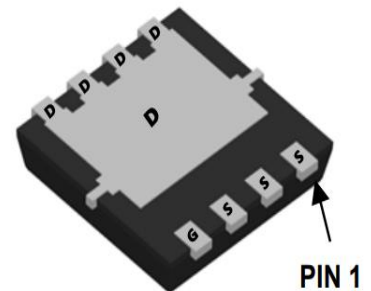
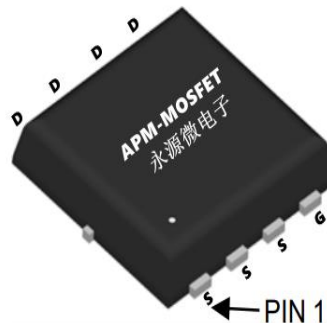
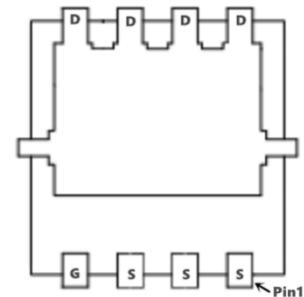
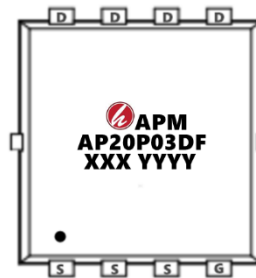
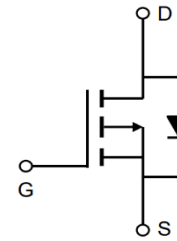
General Features

$V_{DS} = -30V$ $I_D = 28A$

$R_{DS(ON)} < 20m\Omega$ @ $V_{GS}=10V$ (Type: 16.5m Ω)

Application

Lithium battery protection
Wireless impact
Mobile phone fast charging



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP20P03DF	PDFN3*3-8L	AP20P03DF XXX YYYY	5000

Absolute Maximum Ratings ($T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_{D@TC=25^{\circ}C}$	Continuous Drain Current, $V_{GS} @ -10V$	-28	A
$I_{D@TC=100^{\circ}C}$	Continuous Drain Current, $V_{GS} @ -10V$	-16	A
I_{DM}	Pulsed Drain Current ²	-80	A
E_{AS}	Single Pulse Avalanche Energy ³	16	mJ
I_{AS}	Avalanche Current	-17	A
$P_{D@TC=25^{\circ}C}$	Total Power Dissipation ⁴	16.6	W
T_{STG}	Storage Temperature Range	-55 to 150	$^{\circ}C$
T_J	Operating Junction Temperature Range	-55 to 150	$^{\circ}C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	85	$^{\circ}C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	3.6	$^{\circ}C/W$

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Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D = -250μA	-30	-33	-	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} = -30V, V _{GS} =0V,	-	-	-1	μA
IGSS	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D = -250μA	-1.2	-1.5	-2.5	V
RDS(on)	Static Drain-Source on-Resistance note3	V _{GS} = -10V, I _D = -10A	-	16.5	20	mΩ
		V _{GS} = -4.5V, I _D = -5A	-	23	30	
C _{iss}	Input Capacitance	V _{DS} = -15V, V _{GS} =0V, f=1.0MHz	-	1250	-	pF
C _{oss}	Output Capacitance		-	327	-	pF
C _{rss}	Reverse Transfer Capacitance		-	278	-	pF
Q _g	Total Gate Charge	V _{DS} = -15V, I _D = -9.1A, V _{GS} = -10V	-	30	-	nC
Q _{gs}	Gate-Source Charge		-	5.3	-	nC
Q _{gd}	Gate-Drain("Miller") Charge		-	7.6	-	nC
td(on)	Turn-on Delay Time	V _{DD} = -15V, I _D = -6A, V _{GS} = -10V, R _{GEN} =2.5Ω	-	14	-	ns
t _r	Turn-on Rise Time		-	20	-	ns
td(off)	Turn-off Delay Time		-	95	-	ns
t _f	Turn-off Fall Time		-	65	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	-10	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-40	A
VSD	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S = -11A	-	-0.8	-1.2	V

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、The EAS data shows Max. rating . The test condition is VDD=-25V,VGS=-10V,L=0.1mH,IAS=-23A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

P-Channel Typical Characteristics

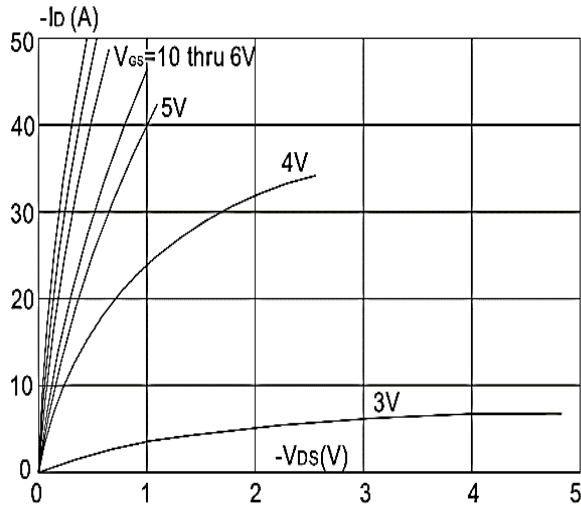


Figure 1: Output Characteristics

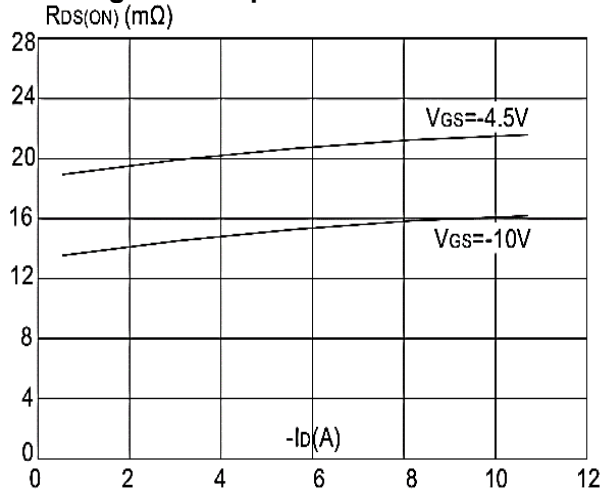


Figure 3: On-resistance vs. Drain Current

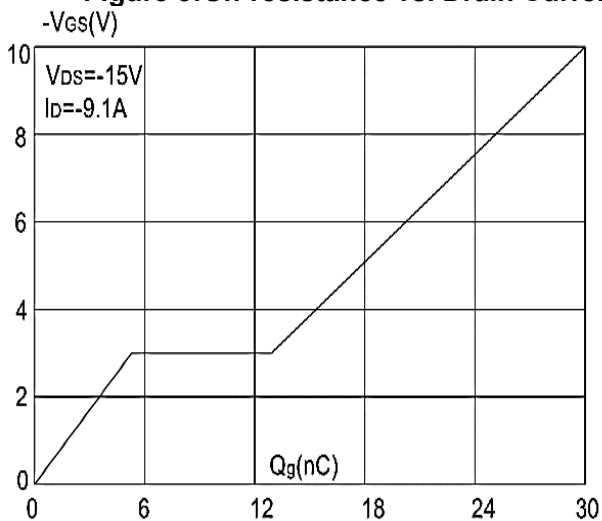


Figure 5: Gate Charge Characteristics

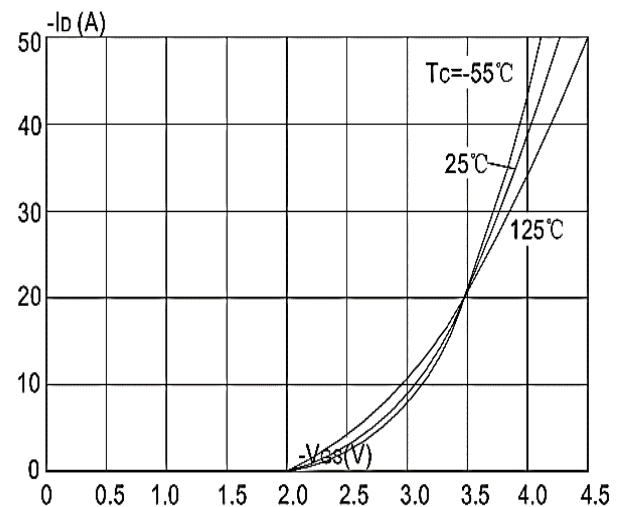


Figure 2: Typical Transfer Characteristics

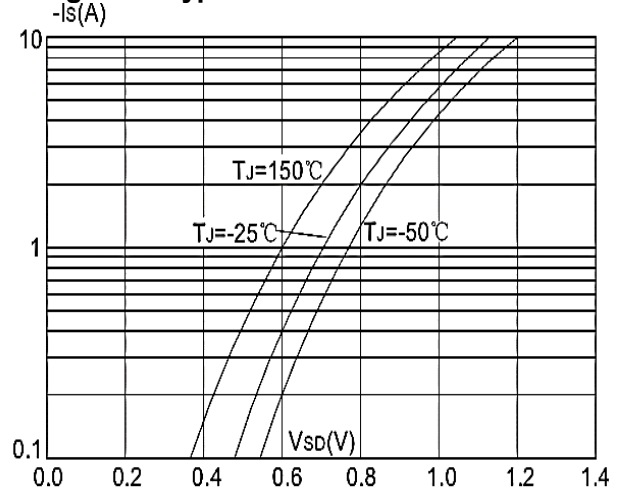


Figure 4: Body Diode Characteristics

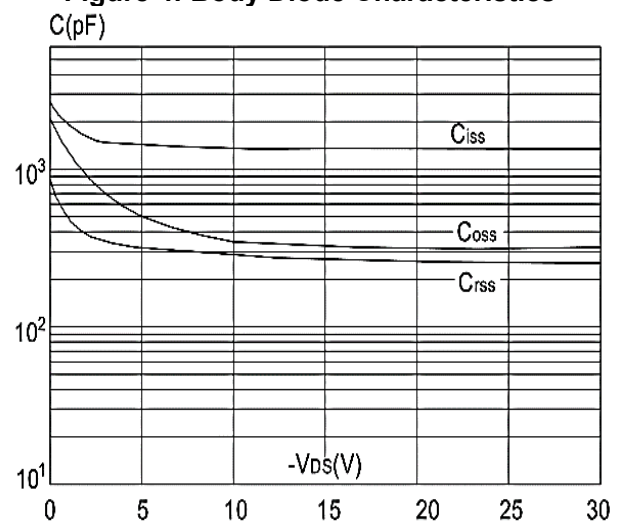


Figure 6: Capacitance Characteristics

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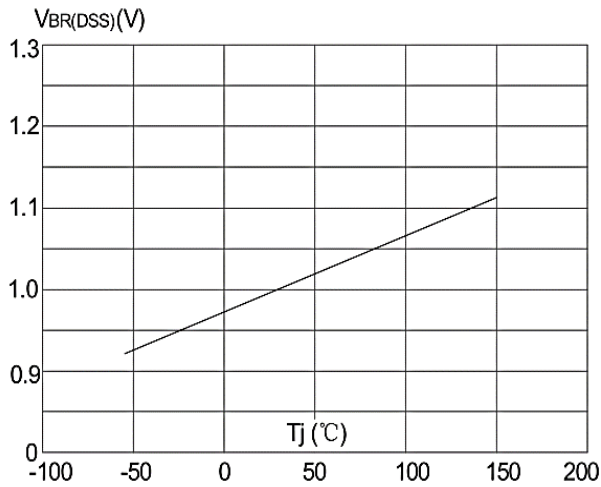


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

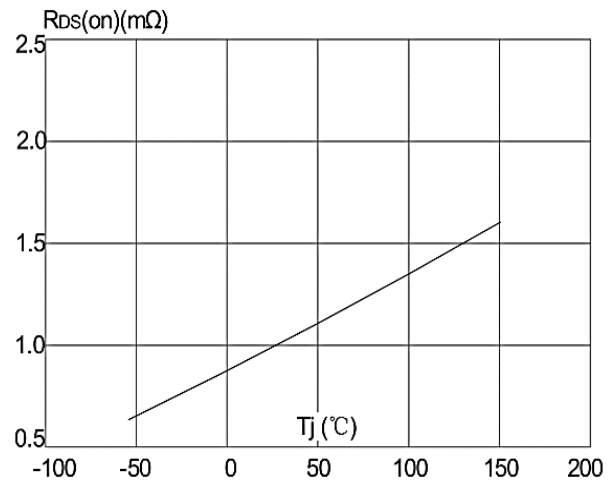


Figure 8: Normalized on Resistance vs. Junction Temperature

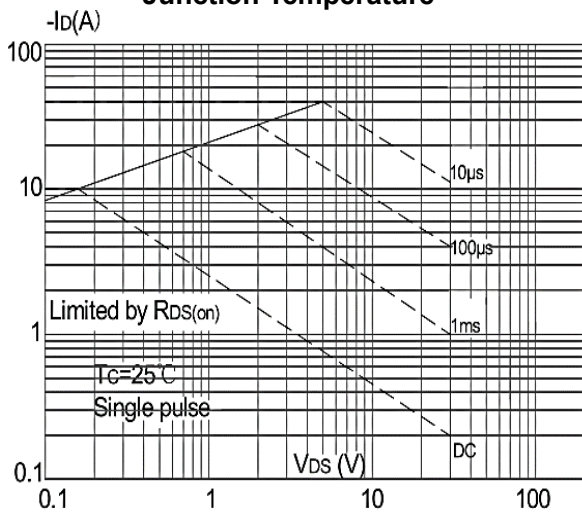


Figure 9: Maximum Safe Operating Area

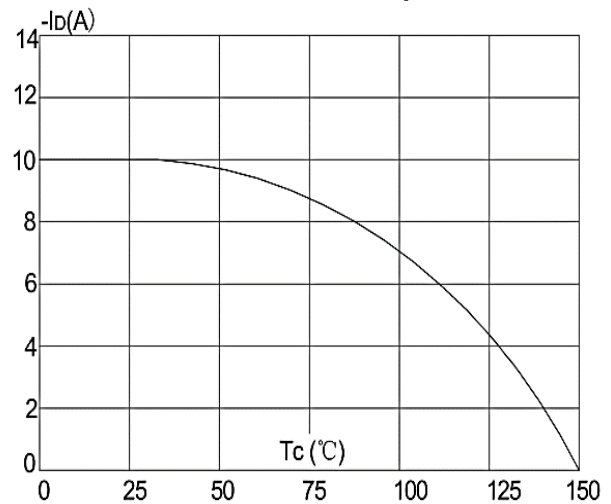


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

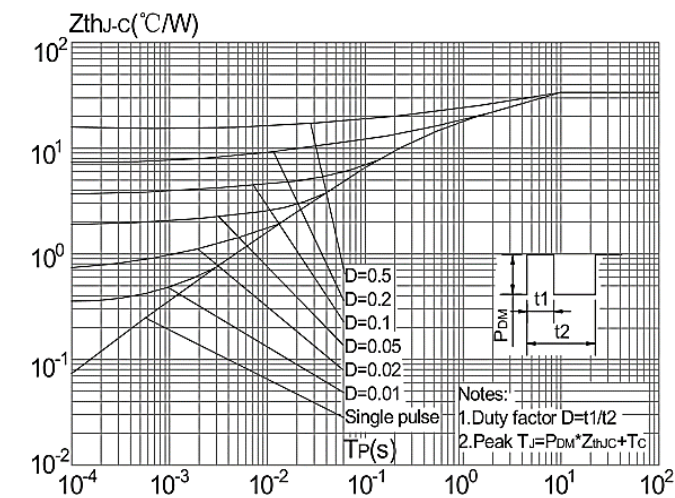
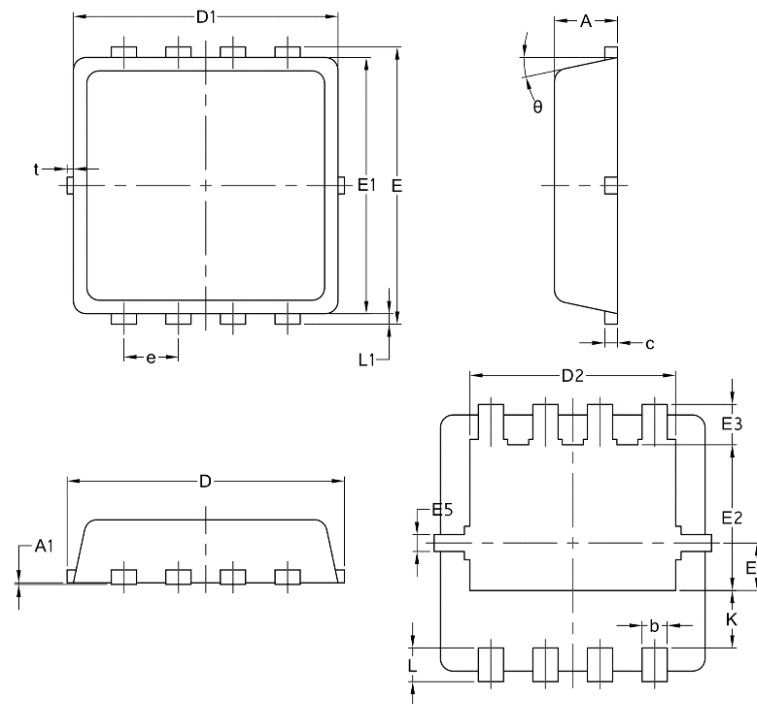


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

Package Mechanical Data-DFN3*3-8L-JQ Single



Symbol	Common		
	mm		
	Mim	Nom	Max
A	0.70	0.75	0.85
A1	/	/	0.05
b	0.20	0.30	0.40
c	0.10	0.152	0.25
D	3.15	3.30	3.45
D1	3.00	3.15	3.25
D2	2.29	2.45	2.65
E	3.15	3.30	3.45
E1	2.90	3.05	3.20
E2	1.54	1.74	1.94
E3	0.28	0.48	0.65
E4	0.37	0.57	0.77
E5	0.10	0.20	0.30
e	0.60	0.65	0.70
K	0.59	0.69	0.89
L	0.30	0.40	0.50
L1	0.06	0.125	0.20
t	0	0.075	0.13
Φ	10	12	14

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Edition	Date	Change
REV1.0	2018/4/10	Initial release
REV1.1	2023/4/4	Reduce RDS (On)

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